

TRENCHSTOPTM RC-Series for hard switching applications

IGBT chip with monolithically integrated diode in packages offering space saving advantage

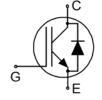
Features:

TRENCHSTOPTM Reverse Conducting (RC) technology for 600V applications offering:

- \bullet Optimised V_{CEsat} and V_{F} for low conduction losses
- Smooth switching performance leading to low EMI levels
- Very tight parameter distribution
- Operating range of 1 to 20kHz
- Maximum junction temperature 175°C
- Short circuit capability of 5µs
- Best in class current versus package size performance

 V_{CE}

- Qualified according to JEDEC for target applications
- Complete product spectrum and PSpice Models: http://www.infineon.com/igbt/



Package

Applications:

Chip Type

Used for:

Motor drives Discrete components and molded modules

Cilib Type	▶ CE	/ Cn	Die Size	Fackage			
IGC10R60DE	600V	15A	2.70 x 3.73 mm ²	sawn on foil			
Mechanical Paramete	ers						
Raster size			2.70	x 3.73	mm ²		
Emitter pad size			see chip	o drawing			
Gate pad size			see chip	o drawing mn			
Area: total / active IGE	BT / active Dic	ode	10.071 / 5	.544 / 1.317			
Thickness			-	70 µn	n		
Wafer size			200				
Max.possible chips per wafer			2759				
Passivation frontside			Photoimide				
Pad metal			3200 nm AlSiCu				
Backside metal			Ni Ag -system				
Die bond			Electrically conductive epoxy glue and soft solder (temperature budget: 290°C for 1min. or 260°C for 1.5min.)				
Wire bond			Al, <350μm				
Reject ink dot size			∅ 0.65mm ; max 1.2mm				
Storage environment	for original a sealed MBB		Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month				
Storage environment for open MBB bags			Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month				

Die Size

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Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	600	V	
DC collector current, limited by $T_{\rm vj\;max}$	I _C	1)	А	
Pulsed collector current, t_p limited by $T_{vj \text{ max}}$	$I_{c,puls}$	45	А	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	$T_{\rm vj,max}$	-40+175	°C	
Operating junction temperature	$T_{vj,op,max}$	-40+175	°C	
Short circuit data $^{2)3)}$ $V_{GE} = 15V$, $V_{CC} = 400V$, $T_{vj} = 150$ °C	tsc	5	μs	
Safe operating area IGBT ^{2)3)}	$I_{C,max} = 30A, \ V_{CE,max} = 600V, \ T_{vj,op} \le T_{vj,op,n}$			
Safe operating area Diode ²⁾	$I_{F,max} = 30A, V_{R,max} = 600V,$			
	P_{max} =12 kW , $T_{vj,op} \le T_{vj,op,max}$			

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
. u.u.noto			min.	typ.	max.	
Collector-Emitter breakdown voltage	$V_{(BR)CES}$	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 0.2 mA	600			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =15A		1.65	2.1	V
Diode Forward Voltage	V _F	V _{GE} =0V, I _F =15A		1.7	2.1	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.25mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.3	5	5.7	
Zero gate voltage collector current	I _{CES}	V_{CE} =600V , V_{GE} =0V			40	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			100	nA
Integrated gate resistor	r _G			none		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter		Symbol	Symbol Conditions		Value		
		Symbol Conditions	min.	typ.	max.	Unit	
Collector-Emitter saturation voltage	<i>T</i> _{vj} =175 °C	V _{CEsat}	V _{GE} =15V, I _C =15A		1.85		V
Input capacitance		Cies	V _{CE} =25V,		961		
Output capacitance		Coes	$V_{GE}=0V$, $f=1MHz$		53		pF
Reverse transfer capacitance		C _{res}	<i>T</i> _{vj} =25 °C		33		

depending on thermal properties of assembly
not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s





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Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on package design and mounting technology and can therefore not be specified for a bare die.

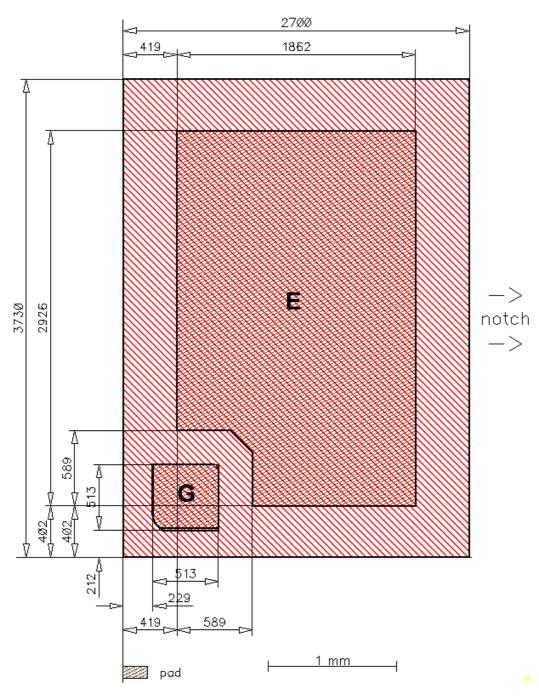
Further technical information about the performance of this chip in package PG-TO252-3 is given exemplarily at www.infineon.com/igbt. The chip qualification is independent of the qualification which is performed for the Discretes.

This chip data sheet refers to the device data sheet IKD15N60R Rev. 2.2



Chip Drawing



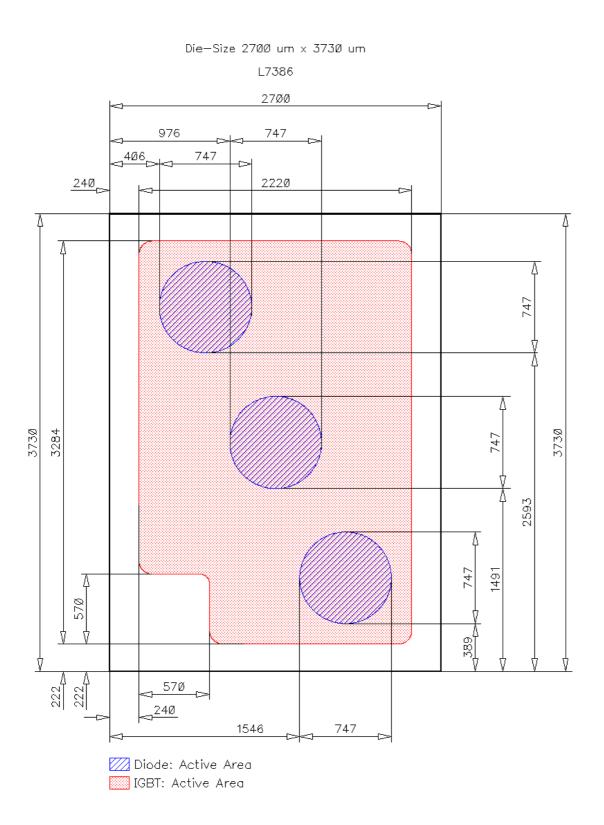


E = Emitter

 $\mathbf{G} = \mathsf{Gate}$



Chip Drawing active areas







TRENCHSTOP[™] RC-Series for hard switching applications

Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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